

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10/060,945	CARRICK ET AL.
	Examiner	Art Unit
	David S. Kim	2613
		Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	So, V.C.Y. et al. "Measuring chromatic dispersion and modal interference with an optical time-domain reflectometer." Optical Engineering. 01 September 1993, Volume 32, Issue 9: 2110-2113.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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